

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/600,637	HAYNER ET AL.
Examiner	Art Unit	
Kim-Kwok CHU	2627	

SEARCHED			
Class	Subclass	Date	Examiner
369	30.14	6/14/2006	KC
369	30.15	6/14/2006	KC
369	44.25	6/14/2006	KC
369	44.38	6/14/2006	KC
369	44.29	6/14/2006	KC
369	44.27	6/14/2006	KC
369	44.34	6/14/2006	KC
369	47.1	6/14/2006	KC
369	53.14	6/14/2006	KC
369	53.28	6/14/2006	kc

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner